



SBAS224B – DECEMBER 2001 – REVISED MAY 2002

**ADS8323**

# **16-Bit, 500kSPS, microPower Sampling ANALOG-TO-DIGITAL CONVERTER**

### **FEATURES**

- **HIGH-SPEED PARALLEL INTERFACE**
- **500kSPS SAMPLING RATE**
- **LOW POWER: 85mW at 500kSPS**
- **BIPOLAR INPUT RANGE**
- **TQFP-32 PACKAGE**

### **APPLICATIONS**

- **HIGH-SPEED DATA AQUISITION**
- **OPTICAL POWER MONITORING**
- **MOTOR CONTROL**
- **ATE**

### **DESCRIPTION**

The ADS8323 is a 16-bit, 500kSPS Analog-to-Digital Converter (ADC) with an internal 2.5V reference. The device includes a 16-bit capacitor-based SAR ADC with inherent sample-and-hold. The ADS8323 offers a full 16-bit interface, or an 8-bit option where data is read using two read cycles.

The ADS8323 is available in a TQFP-32 package and is specified over the industrial –40°C to +85°C temperature range.





Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

**PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.**



#### **PACKAGE/ORDERING INFORMATION**



NOTE: (1) For the most current specifications and package information, refer to our web site at www.ti.com.

#### **ABSOLUTE MAXIMUM RATINGS**

Absolute Maximum Ratings over operating free-air temperature (unless otherwise noted)(1)



NOTE: (1) Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions of extended periods may affect device reliability.

#### **RECOMMENDED OPERATING CONDITIONS**



NOTE: (1) The voltage difference between  $AV<sub>DD</sub>$  and  $DV<sub>DD</sub>$  terminals cannot exceed 0.3V to maintain performance specifications.

#### **EQUIVALENT INPUT CIRCUIT**



### **ELECTROSTATIC DISCHARGE SENSITIVITY**

This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.



NOTE: (1) This is the inverse of the traditional junction-to-ambient thermal resistance ( $R_{\theta J}$ ). Thermal resistances are not production tested and are for informational purposes only.





## **ELECTRICAL CHARACTERISTICS**

At –40°C to +85°C, +DV<sub>DD</sub> = +AV<sub>DD</sub> = +5V, V<sub>REF</sub> = +2.5V,  $f_{SAMPLE} = 500kSPS$ , and  $f_{CLK} = 20 \cdot f_{SAMPLE}$ , unless otherwise specified.



✻ Specifications same as ADS8323Y.

NOTES: (1) Ideal input span; does not include gain or offset error. (2) LSB means Least Signifcant Bit, with V<sub>REF</sub> equal to +2.5V; 1LSB = 76µV. (3) Measured relative to an ideal, full-scale input (+In – (–In)) of 4.9999V. Thus, gain error includes the error of the internal voltage reference. (4) Calculated on the first nine harmonics of the input frequency.





### **TIMING CHARACTERISTICS(1)(2)**

All specifications typical at  $-40^{\circ}$ C to  $+85^{\circ}$ C,  $+DV_{DD} = +5V$ .



NOTES: (1) All input signals are specified with rise and fall times of 5ns,  $t_R = t_F = 5$ ns (10% to 90% of DV<sub>DD</sub>), and timed from a voltage level of (V<sub>IL</sub> + V<sub>IH</sub>)/2. (2) See timing diagram, below. (3) BYTE is asynchronous; when BYTE is 0, bits 15 through 0 appear at DB15-DB0. When BYTE is 1, bits 15 through 8 appear on DB7-DB0. RD may remain LOW between changes in BYTE.



### **TIMING DIAGRAM**





#### **PIN CONFIGURATION**



#### **PIN ASSIGNMENTS**



NOTE: AI is Analog Input, AO is Analog Output, DI is Digital Input, DO is Digital Output, and P is Power-Supply Connection.





### **TYPICAL CHARACTERISTICS**

At  $-40^{\circ}$ C to +85 $^{\circ}$ C, +DV<sub>DD</sub> = +AV<sub>DD</sub> = +5V, V<sub>REF</sub> = +2.5V,  $f_{SAMPLE} = 500kSPS$ , and  $f_{CLK} = 20 \cdot f_{SAMPLE}$ , unless otherwise specified.







### **TYPICAL CHARACTERISTICS (Cont.)**

At  $-40^{\circ}$ C to +85 $^{\circ}$ C, +DV<sub>DD</sub> = +AV<sub>DD</sub> = +5V, V<sub>REF</sub> = +2.5V,  $f_{SAMPLE} = 500kSPS$ , and  $f_{CLK} = 20 \cdot f_{SAMPLE}$ , unless otherwise specified.















### **TYPICAL CHARACTERISTICS (Cont.)**

At  $-40^{\circ}$ C to +85 $^{\circ}$ C, +DV<sub>DD</sub> = +AV<sub>DD</sub> = +5V, V<sub>REF</sub> = +2.5V,  $f_{SAMPLE} = 500kSPS$ , and  $f_{CLK} = 20 \cdot f_{SAMPLE}$ , unless otherwise specified.





### **THEORY OF OPERATION**

The ADS8323 is a high-speed Successive Approximation Register (SAR) 16-bit ADC with an internal 2.5V bandgap reference that operates from a single +5V supply. The input is fully differential with a typical common-mode rejection of 70dB. The part accepts a differential analog input voltage in the range of  $-V_{REF}$  to  $+V_{REF}$ , centered on the common-mode voltage (see the Analog Input section). The part will also accept bipolar input ranges when a level shift circuit is used at the front end (see Figure 7). See Figure 1 for the basic operating circuit for the ADS8323.

The ADS8323 requires an external clock to run the conversion process. This clock can vary between 25kHz (1.25kHz throughput) and 10MHz (500kSPS throughput). The duty cycle of the clock is unimportant as long as the minimum HIGH and LOW times are at least 40ns and the clock period is at least 100ns. The minimum clock frequency is governed by the parasitic leakage of the Capacitive Digital-to-Analog Converter (CDAC) capacitors internal to the ADS8323.

The analog input is provided to two input pins, +IN and –IN. When a conversion is initiated, the differential input on these pins is sampled on the internal capacitor array. A conversion is initiated on the ADS8323 by bringing CONVST (pin 21) LOW for a minimum of 20ns. CONVST LOW places the sample-and-hold amplifier in the hold state and the conversion process is started. The BUSY output (pin 17) will go HIGH when the conversion begins and will stay HIGH during the conversion. While a conversion is in progress, both inputs are disconnected from any internal function. When the conversion result is latched into the output register, the BUSY signal will go LOW. The data can be read from the parallel output bus following the conversion by bringing both RD and CS LOW.

NOTE: This mode of operation is described in more detail in the Timing and Control section of this data sheet.

#### **SAMPLE-AND-HOLD SECTION**

The sample-and-hold on the ADS8323 allow the ADC to accurately convert an input sine wave of full-scale amplitude to 16-bit resolution. The input bandwidth of the sample-andhold is greater than the Nyquist rate (Nyquist equals one-half of the sampling rate) of the ADC even when the ADC is operated at its maximum throughput rate of 500kSPS. The typical small-signal bandwidth of the sample-and-hold amplifier is 20MHz. Typical aperture delay time, or the time it takes for the ADS8323 to switch from the sample to the hold mode following the negative edge of the CONVST signal, is 10ns. The average delta of repeated aperture delay values is typically 30ps (also known as aperture jitter). These specifications reflect the ability of the ADS8323 to capture AC input signals accurately at the exact same moment in time.

#### **REFERENCE**

If the internal reference is used,  $REF_{OUT}$  (pin 32) should be directly connected to  $REF_{IN}$  (pin 31). The ADS8323 can operate, however, with an external reference in the range of 1.5V to 2.55V for a corresponding full-scale range of 3.0V to 5.1V. The internal reference of the ADS8323 is doublebuffered. If the internal reference is used to drive an external load, a buffer is provided between the reference and the load applied to  $REF<sub>OUT</sub>$  (pin 32) (the internal reference can typically source or sink 10µA of current; compensation capacitance should be at least  $0.1\mu$ F to minimize noise). If an external reference is used, the second buffer provides isolation between the external reference and the CDAC. This buffer is also used to recharge all of the capacitors of the CDAC during conversion.







FIGURE 1. Typical Circuit Configuration.

#### **ANALOG INPUT**

The analog input is bipolar and fully differential. There are two general methods of driving the analog input of the ADS8323: single-ended or differential, as shown in Figures 2 and 3. When the input is single-ended, the –IN input is held at the common-mode voltage. The +IN input swings around the same common voltage and the peak-to-peak amplitude is the (common-mode +  $V_{RFE}$ ) and the (common-mode –  $V_{RFE}$ ). The value of  $V_{REF}$  determines the range over which the common-mode voltage may vary (see Figure 4).



FIGURE 2. Methods of Driving the ADS8323 either Single-Ended or Differential.

When the input is differential, the amplitude of the input is the difference between the +IN and  $-IN$  input, or  $(+IN) - (-IN)$ . The peak-to-peak amplitude of each input is  $\pm 1/2V_{REF}$  around this common voltage. However, since the inputs are 180° out-of-phase, the peak-to-peak amplitude of the differential voltage is  $+V_{REF}$  to  $-V_{REF}$ . The value of  $V_{REF}$  also determines the range of the voltage that may be common to both inputs (see Figure 5).

In each case, care should be taken to ensure that the output impedance of the sources driving the +IN and –IN inputs are matched. If matching is not observed, it may result in offset error, which changes with temperature. Often, a small capacitor (20pF) between the positive and negative inputs helps to match their impedance.

The input current on the analog inputs depends on a number of factors: sample rate, input voltage, and source impedance. Essentially, the current into the ADS8323 charges the internal capacitor array during the sampling period. After this capacitance has been fully charged, there is no further input current. The source of the analog input voltage must be able to charge the input capacitance (25pF) to a 16-bit settling level within 4 clock cycles (400ns), if the minimum acquisition time is used. When the converter goes into the hold mode, the input impedance is greater than 1GΩ.

Care must be taken regarding the absolute analog input voltage. The +IN and –IN inputs should always remain within the range of AGND – 0.3V to  $AV_{DD}$  + 0.3V.







FIGURE 3. Using the ADS8323 in the Single-Ended and Differential Input Modes.



FIGURE 4. Single-Ended Input: Common-Mode Voltage Range vs V<sub>REF</sub>.



FIGURE 5. Differential Input: Common-Mode Voltage Range vs V<sub>REF</sub>.



#### **NOISE**

Figure 6 shows the transition noise of the ADS8323. A lowlevel DC input was applied to the analog-input pins and the converter was put through 8192 conversions. The digital output of the ADC will vary in output code due to the internal noise of the ADS8323. This is true for all 16-bit SAR-type ADCs. The ADS8323, with five output codes for the σ distribution, will yield  $a < \pm 0.8$ LSB transition noise at 5V operation. Remember that to achieve this low-noise performance, the peak-to-peak noise of the input signal and reference must be  $<$  50 $\mu$ V.



FIGURE 6. Histogram of 8192 Conversions of a Low-Level DC Input.

#### **AVERAGING**

Averaging the digital codes can compensate the noise of the ADC. By averaging conversion results, transition noise will be reduced by a factor of  $1/\sqrt{n}$ , where n is the number of averages. For example, averaging 4 conversion results will reduce the transition noise by  $1/2$  to  $\pm$ 0.4LSB. Averaging should only be used for input signals with frequencies near DC. For AC signals, a digital filter can be used to low-pass filter and decimate the output codes. This works in a similar manner to averaging—for every decimation by 2, the signal-to-noise ratio will improve 3dB.

#### **BIPOLAR INPUTS**

The differential inputs of the ADS8323 were designed to accept bipolar inputs ( $-V_{REF}$  and  $+V_{REF}$ ) around the common-mode voltage, which corresponds to a 0V to 5V input range with a 2.5V reference. By using a simple op amp circuit featuring four high-precision external resistors, the ADS8323 can be configured to accept bipolar inputs. The conventional ±2.5V, ±5V, and ±10V input ranges could be interfaced to the ADS8323 using the resistor values shown in Figure 7.



FIGURE 7. Level Shift Circuit for Bipolar Input Ranges.

# **DIGITAL INTERFACE**

#### **TIMING AND CONTROL**

See the timing diagram in the Timing Characteristics section for detailed information on timing signals and their requirements.

The ADS8323 uses an external clock (CLOCK, pin 20) that controls the conversion rate of the CDAC. With a 10MHz external clock, the ADC sampling rate is 500kSPS that corresponds to a 2µs maximum throughput time.

#### **EXPLANATION OF CLOCK, BUSY AND BYTE PINS**

**CLOCK—**An external clock must be provided for the ADS8323. The maximum clock frequency is 10MHz and that provides 500kSPS throughput. The minimum clock frequency is 25kHz and that provides 1.25kHz throughput. The minimum clock cycle is 100ns (see Timing Diagram,  $t_{C1}$ ), and CLOCK must remain HIGH (see Timing Diagram,  $t_{W1}$ ) or LOW (see Timing Diagram,  $t_{W2}$ ) for at least 40ns.

**BUSY—**Initially BUSY output is LOW. Reading data from output register or sampling the input analog signal will not affect the state of the BUSY signal. After the CONVST input goes LOW and conversion starts, a maximum of 25ns later the BUSY output will go HIGH. That signal will stay HIGH during conversion and will provide the status of the internal ADC to the DSP or uC. At the end of conversion, on the rising edge of 17th clock cycle, new data from the internal ADC is latched into the output registers. The BUSY signal will go LOW a maximum of 25ns later (see Timing Diagram,  $t_{D4}$ ).

**BYTE—**The output data will appear as a full 16-bit word on DB15-DB0 (MSB-LSB or D15-D0) if BYTE is LOW. If there is only an 8-bit bus available on a board, the result may also be read on an 8-bit bus by using only DB7-DB0. In this case, two reads are necessary (see Timing Diagram). The first, as before, leaving BYTE LOW and reading the 8 least significant bits on DB7-DB0, then bringing BYTE HIGH. When BYTE is HIGH, the upper 8 bits (D15-D8) will appear on DB7-DB0.





#### **START OF A CONVERSION AND READING DATA**

By bringing the CONVST signal LOW, the input data is immediately placed in the hold mode (10ns). Although CS must be LOW when CONVST goes LOW to initiate a conversion. The conversion follows with the next rising edge of CLOCK. If it is important to detect a hold command during a certain clock cycle, then the falling edge of the CONVST signal must occur at least 10ns before the rising edge of CLOCK (see Timing Diagram,  $t_{D1}$ ). The CONVST signal can remain LOW without initiating a new conversion. The CONVST signal must be HIGH for at least 20ns (see Timing Diagram,  $t_{W4}$ ) before it is brought LOW again and CONVST must stay LOW for at least 20ns (see Timing Diagram,  $t_{W3}$ ). Once a CONVST signal goes LOW, further impulses of this signal are ignored until the conversion is finished or the part is reset.

When the conversion is finished (after 16 clock cycles) the sampling switches will close and sample the new value. The start of the next conversion must be delayed to allow the input capacitor of the ADS8323 to be fully charged. This delay time depends on the driving amplifier, but should be at least 400ns. To gain acquisition time, the falling edge of CONVST must take place just before the rising edge of CLOCK (see Timing Diagram,  $t_{D1}$ ). One conversion cycle requires 20 clock cycles. However, reading data during the conversion or on a falling hold edge might cause a loss in performance.

**Reading Data (RD, CS)—**In general, the data outputs are in tri-state. Both  $\overline{CS}$  and  $\overline{RD}$  must be LOW to enable these outputs.  $\overline{RD}$  and  $\overline{CS}$  must stay LOW together for at least 40ns (see Timing Diagram,  $t_{D7}$ ) before the output data is valid. RD must remain HIGH for at least 20ns (see Timing Diagram,  $t_{W7}$ ) before bringing it back LOW for a subsequent read command. 16 clock-cycles after the start of a conversion (next rising edge of clock after the falling edge of CONVST), the new data is latched into the output register and the reading process can start again.

CS being LOW tells the ADS8323 that the bus on the board is assigned to the ADS8323. If an ADC shares a bus with digital gates, there is a possibility that digital (high-frequency) noise gets coupled into the ADC. If the bus is just used by the ADS8323,  $\overline{CS}$  can be hard-wired to ground. The output data should not be read 125ns prior to the falling edge of CONVST and 10ns after the falling edge.

The ADS8323's output is in Binary Two's Complement format (see Figure 8).



TABLE I. Ideal Input Voltages and Output Codes.

### **LAYOUT**

For optimum performance, care should be taken with the physical layout of the ADS8323 circuitry. This is particularly true if the CLOCK input is approaching the maximum throughput rate.

As the ADS8323 offers single-supply operation, it will often be used in close proximity with digital logic, microcontrollers, microprocessors, and digital signal processors. The more digital logic present in the design and the higher the switching speed, the more difficult it will be to achieve good performance from the converter.

The basic SAR architecture is sensitive to glitches or sudden changes on the power supply, reference, ground connections, and digital inputs that occur just prior to latching the output of the analog comparator. Thus, during any single conversion for an n-bit SAR converter, there are n "windows" in which large external transient voltages can affect the conversion result. Such glitches might originate from switching power supplies, nearby digital logic, or high-power devices.

The degree of error in the digital output depends on the reference voltage, layout, and the exact timing of the external event. Their error can change if the external event changes in time with respect to the CLOCK input.

On average, the ADS8323 draws very little current from an external reference as the reference voltage is internally buffered. If the reference voltage is external and originates from an op amp, make sure that it can drive the bypass capacitor or capacitors without oscillation. A 0.1µF bypass capacitor is recommended from pin 31 directly to ground.

The AGND and DGND pins should be connected to a clean ground point. In all cases, this should be the "analog" ground. Avoid connections which are too close to the grounding point of a microcontroller or digital signal processor. If required, run a ground trace directly from the converter to the powersupply entry point. The ideal layout will include an analog ground plane dedicated to the converter and associated analog circuitry.

As with the GND connections,  $V_{DD}$  should be connected to a +5V power supply plane, or trace, that is separate from the connection for digital logic until they are connected at the power entry point. Power to the ADS8323 should be clean and well bypassed. A 0.1µF ceramic bypass capacitor should be placed as close to the device as possible. In addition, a 1µF to 10µF capacitor is recommended. If needed, an even larger capacitor and a 5 $\Omega$  or 10 $\Omega$  series resistor may be used to low-pass filter a noisy supply. In some situations, additional bypassing may be required, such as a 100µF electrolytic capacitor, or even a Pi filter made up of inductors and capacitors all designed to essentially low-pass filter the +5V supply, removing the high-frequency noise.











#### **PACKAGE DRAWING**

#### **PBS (S-PQFP-G32) PLASTIC QUAD FLATPACK**



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.





#### **PACKAGING INFORMATION**



**(1)** The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

**LIFEBUY:** TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

**NRND:** Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

**PREVIEW:** Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

**(2)** Eco Plan - May not be currently available - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

**None:** Not yet available Lead (Pb-Free).

**Pb-Free (RoHS):** TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

**Green (RoHS & no Sb/Br):** TI defines "Green" to mean "Pb-Free" and in addition, uses package materials that do not contain halogens, including bromine (Br) or antimony (Sb) above 0.1% of total product weight.

**(3)** MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDECindustry standard classifications, and peak solder temperature.

**Important Information and Disclaimer:**The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

#### **IMPORTANT NOTICE**

Texas Instruments Incorporated and its subsidiaries (TI) reserve the right to make corrections, modifications, enhancements, improvements, and other changes to its products and services at any time and to discontinue any product or service without notice. Customers should obtain the latest relevant information before placing orders and should verify that such information is current and complete. All products are sold subject to TI's terms and conditions of sale supplied at the time of order acknowledgment.

TI warrants performance of its hardware products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are used to the extent TI deems necessary to support this warranty. Except where mandated by government requirements, testing of all parameters of each product is not necessarily performed.

TI assumes no liability for applications assistance or customer product design. Customers are responsible for their products and applications using TI components. To minimize the risks associated with customer products and applications, customers should provide adequate design and operating safeguards.

TI does not warrant or represent that any license, either express or implied, is granted under any TI patent right, copyright, mask work right, or other TI intellectual property right relating to any combination, machine, or process in which TI products or services are used. Information published by TI regarding third-party products or services does not constitute a license from TI to use such products or services or a warranty or endorsement thereof. Use of such information may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

Reproduction of information in TI data books or data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. Reproduction of this information with alteration is an unfair and deceptive business practice. TI is not responsible or liable for such altered documentation.

Resale of TI products or services with statements different from or beyond the parameters stated by TI for that product or service voids all express and any implied warranties for the associated TI product or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

Following are URLs where you can obtain information on other Texas Instruments products and application solutions:



Mailing Address: Texas Instruments

Post Office Box 655303 Dallas, Texas 75265

Copyright 2004, Texas Instruments Incorporated